

MTD3055VL

N-Channel Logic Level Enhancement Mode Field Effect Transistor

General Description

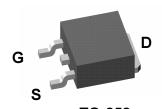
This N-Channel Logic Level MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers.

These MOSFETs feature faster switching and lower gate charge than other MOSFETs with comparable $\rm R_{\rm DS(ON)}$ specifications.

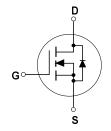
The result is a MOSFET that is easy and safer to drive (even at very high frequencies), and DC/DC power supply designs with higher overall efficiency.

Features

- 12 A, 60 V. $R_{DS(ON)}$ = 0.18 Ω @ V_{GS} = 5 V
- Critical DC electrical parameters specified at elevated temperature.
- Low drive requirements allowing operation directly from logic drivers. Vgs(th) < 2 V.
- Rugged internal source-drain diode can eliminate the need for an external Zener diode transient suppressor.
- 175°C maximum junction temperature rating.







Absolute	Maximum	Ratings	Tc=25°C unless otherwise noted	
Symbol		Parame	oter	

Symbol	Parameter	Ratings	Units
V _{DSS}	Drain-Source Voltage	60	V
V _{GSS}	Gate-Source Voltage	±20	V
I _D	Maximum Drain Current -Continuous (Note 1)	12	Α
	T _C = 100°C (Note 1)	8	
	Maximum Drain Current -Pulsed	42	
P _D	Maximum Power Dissipation @ T _C = 25°C (Note 1)	48	W
	T _A = 25°C (Note 1a)	3.9	
	T _A = 25°C (Note 1b)	1.5	
T _J , T _{STG}	Operating and Storage Junction Temperature Range	-55 to +175	∘C

Thermal Characteristics

R _{eJC}	Thermal Resistance, Junction-to- Case	(Note 1)	3.13	∘C/W
R _{e,IA}	Thermal Resistance, Junction-to- Ambient	(Note 1a)	71.4	∘C/W

Package Marking and Ordering Information

Device Marking	Device	Reel Size	Tape width	Quantity
MTD3055VL	MTD3055VL	13"	16mm	2500

^{*} Die and manufacturing source subject to change without prior notification.

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Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
DRAIN-S	OURCE AVALANCHE RAT	INGS (Note 2)			ļ	!
W _{DSS}	Single Pulse Drain-Source Avalanche Energy	V _{DD} = 25 V, I _D = 12 A			72	mJ
l _{AR}	Maximum Drain-Source Avalanche	Current			12	Α
Off Chara	acteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 \text{ V}, I_{D} = 250 \mu\text{A}$	60			V
$\frac{\Delta BV_DSS}{\Delta T_J}$	Breakdown Voltage Temperature Coefficient	I _D = 250 _μ A, Referenced to 25°C		54		mV/∘C
DSS	Zero Gate Voltage Drain Current	V _{DS} = 60 V, V _{GS} = 0 V			10	μΑ
		V _{DS} = 60 V, V _{GS} = 0 V, T _J = 150°C			100	
GSSF	Gate-Body Leakage Current, Forward	V _{GS} = 15 V, V _{DS} = 0 V			100	nA
GSSR	Gate-Body Leakage Current, Reverse	V _{GS} = -15 V, V _{DS} = 0 V			-100	nA
On Chara	acteristics (Note 2)					
$V_{\text{GS}(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	1	1.5	2	V
$\frac{\Delta V^{\text{GS(th)}}}{\Delta T_{\text{J}}}$	Gate Threshold Voltage Temperature Coefficient	I _D = 250 μA, Referenced to 25°C		-2.6		mV/∘C
R _{DS(on)}	Static Drain-Source On-Resistance	$V_{GS} = 5 V_1 I_D = 6 A_1$			0.18	Ω
$V_{DS(on)}$	Drain-Source On-Voltage On-Resistance	V _{GS} = 5 V, I _D = 12 A I _D = 6 A, T _J =150∘C			2.6 2.5	V
g _{FS}	Forward Transconductance	$V_{DS} = 8 V, I_{D} = 6 A$	5.0			S
<u>Dynamic</u>	Characteristics					
C _{iss}	Input Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$			570	pF
Coss	Output Capacitance	f = 1.0 MHz			160	pF
C_{rss}	Reverse Transfer Capacitance				40	pF
Switchin	g Characteristics (Note 2)					
t _{d(on)}	Turn-On Delay Time	$V_{DD} = 30 \text{ V}, I_D = 12 \text{ A},$			20	ns
tr	Turn-On Rise Time	$V_{GS} = 5 \text{ V}, R_{GEN} = 9.1 \Omega$			190	ns
t _{d(off)}	Turn-Off Delay Time	1			30	ns
t _f	Turn-Off Fall Time	1			90	ns
Q _g	Total Gate Charge	V _{DS} = 48 V,			10	nC
Q _{gs}	Gate-Source Charge	$I_D = 12 \text{ A}, V_{GS} = 5 \text{ V}$		2		nC
Q _{gd}	Gate-Drain Charge	1		6.1		nC
	urce Diode Characteristics	and Maximum Ratings				
Is	Maximum Continuous Drain-Source				12	А
I _{SM}	Maximum Pulsed Drain-Source Die				42	Α
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V, } I_S = 12 \text{ A}$ (Note 2)			1.3	V
t _{rr}	Drain-Source Reverse Recovery Time	$I_F = 12 \text{ A, di/dt} = 100 \text{A/}_{\mu}\text{s}$		51		nS



Scale 1 : 1 on letter size paper 2. Pulse Test: Pulse Width ≤ 300 μs, Duty Cycle ≤ 2.0%

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